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## Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

## Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

### Details

Product Status	Active
Number of LABs/CLBs	858
Number of Logic Elements/Cells	6864
Total RAM Bits	245760
Number of I/O	278
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	332-FBGA
Supplier Device Package	332-CABGA (17x17)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmx02-7000ze-1bg332c">https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmx02-7000ze-1bg332c</a>

## Features

### ■ Flexible Logic Architecture

- Six devices with 256 to 6864 LUT4s and 18 to 334 I/Os

### ■ Ultra Low Power Devices

- Advanced 65 nm low power process
- As low as 22  $\mu$ W standby power
- Programmable low swing differential I/Os
- Stand-by mode and other power saving options

### ■ Embedded and Distributed Memory

- Up to 240 kbits sysMEM™ Embedded Block RAM
- Up to 54 kbits Distributed RAM
- Dedicated FIFO control logic

### ■ On-Chip User Flash Memory

- Up to 256 kbits of User Flash Memory
- 100,000 write cycles
- Accessible through WISHBONE, SPI, I<sup>2</sup>C and JTAG interfaces
- Can be used as soft processor PROM or as Flash memory

### ■ Pre-Engineered Source Synchronous I/O

- DDR registers in I/O cells
- Dedicated gearing logic
- 7:1 Gearing for Display I/Os
- Generic DDR, DDRX2, DDRX4
- Dedicated DDR/DDR2/LPDDR memory with DQS support

### ■ High Performance, Flexible I/O Buffer

- Programmable sysIO™ buffer supports wide range of interfaces:
  - LVCMOS 3.3/2.5/1.8/1.5/1.2
  - LVTTTL
  - PCI
  - LVDS, Bus-LVDS, MLVDS, RSDS, LVPECL
  - SSTL 25/18
  - HSTL 18
  - Schmitt trigger inputs, up to 0.5 V hysteresis
- I/Os support hot socketing
- On-chip differential termination
- Programmable pull-up or pull-down mode

### ■ Flexible On-Chip Clocking

- Eight primary clocks
- Up to two edge clocks for high-speed I/O interfaces (top and bottom sides only)
- Up to two analog PLLs per device with fractional-n frequency synthesis
  - Wide input frequency range (7 MHz to 400 MHz)

### ■ Non-volatile, Infinitely Reconfigurable

- Instant-on – powers up in microseconds
- Single-chip, secure solution
- Programmable through JTAG, SPI or I<sup>2</sup>C
- Supports background programming of non-volatile memory
- Optional dual boot with external SPI memory

### ■ TransFR™ Reconfiguration

- In-field logic update while system operates

### ■ Enhanced System Level Support

- On-chip hardened functions: SPI, I<sup>2</sup>C, timer/counter
- On-chip oscillator with 5.5% accuracy
- Unique TraceID for system tracking
- One Time Programmable (OTP) mode
- Single power supply with extended operating range
- IEEE Standard 1149.1 boundary scan
- IEEE 1532 compliant in-system programming

### ■ Broad Range of Package Options

- TQFP, WLCSP, ucBGA, csBGA, caBGA, ftBGA, fpBGA, QFN package options
- Small footprint package options
  - As small as 2.5 mm x 2.5 mm
- Density migration supported
- Advanced halogen-free packaging

More information on the input gearbox is available in TN1203, [Implementing High-Speed Interfaces with MachXO2 Devices](#).

## Output Gearbox

Each PIC on the top edge has a built-in 8:1 output gearbox. Each of these output gearboxes may be programmed as a 7:1 serializer or as one ODDR4 (8:1) gearbox or as two ODDR2 (4:1) gearboxes. Table 2-10 shows the gearbox signals.

**Table 2-10. Output Gearbox Signal List**

Name	I/O Type	Description
Q	Output	High-speed data output
D[7:0]	Input	Low-speed data from device core
Video TX(7:1): D[6:0]		
GDDR4(8:1): D[7:0]		
GDDR2(4:1)(IOL-A): D[3:0]		
GDDR2(4:1)(IOL-C): D[7:4]		
SCLK	Input	Slow-speed system clock
ECLK [1:0]	Input	High-speed edge clock
RST	Input	Reset

The gearboxes have three stage pipeline registers. The first stage registers sample the low-speed input data on the low-speed system clock. The second stage registers transfer data from the low-speed clock registers to the high-speed clock registers. The third stage pipeline registers controlled by high-speed edge clock shift and mux the high-speed data out to the sysIO buffer. Figure 2-17 shows the output gearbox block diagram.

There are some limitations on the use of the hardened user SPI. These are defined in the following technical notes:

- TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) (Appendix B)
- TN1205, [Using User Flash Memory and Hardened Control Functions in MachXO2 Devices](#)

**Figure 2-22. SPI Core Block Diagram**

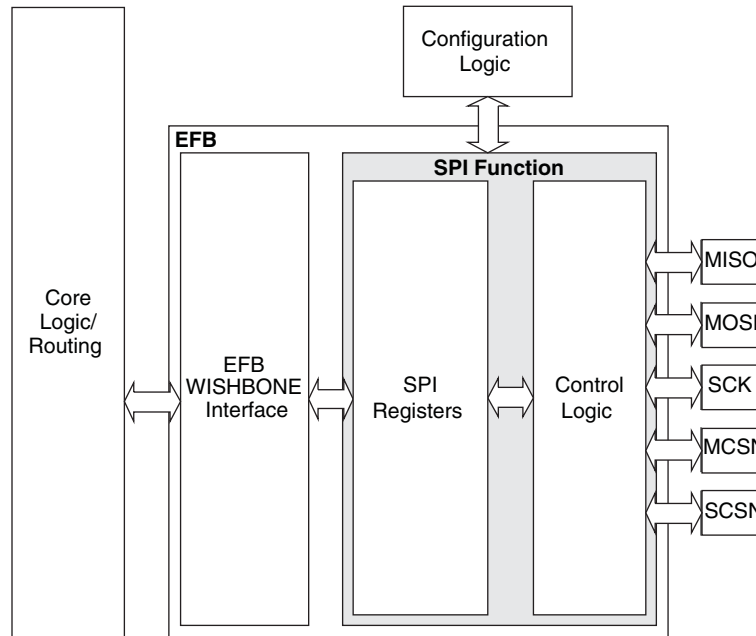


Table 2-16 describes the signals interfacing with the SPI cores.

**Table 2-16. SPI Core Signal Description**

Signal Name	I/O	Master/Slave	Description
spi_csn[0]	O	Master	SPI master chip-select output
spi_csn[1..7]	O	Master	Additional SPI chip-select outputs (total up to eight slaves)
spi_scsn	I	Slave	SPI slave chip-select input
spi_irq	O	Master/Slave	Interrupt request
spi_clk	I/O	Master/Slave	SPI clock. Output in master mode. Input in slave mode.
spi_miso	I/O	Master/Slave	SPI data. Input in master mode. Output in slave mode.
spi_mosi	I/O	Master/Slave	SPI data. Output in master mode. Input in slave mode.
ufm_sn	I	Slave	Configuration Slave Chip Select (active low), dedicated for selecting the User Flash Memory (UFM).
cfg_stdbby	O	Master/Slave	Stand-by signal – To be connected only to the power module of the MachXO2 device. The signal is enabled only if the “Wakeup Enable” feature has been set within the EFB GUI, SPI Tab.
cfg_wake	O	Master/Slave	Wake-up signal – To be connected only to the power module of the MachXO2 device. The signal is enabled only if the “Wakeup Enable” feature has been set within the EFB GUI, SPI Tab.

**Table 2-18. MachXO2 Power Saving Features Description**

Device Subsystem	Feature Description
Bandgap	The bandgap can be turned off in standby mode. When the Bandgap is turned off, analog circuitry such as the POR, PLLs, on-chip oscillator, and referenced and differential I/O buffers are also turned off. Bandgap can only be turned off for 1.2 V devices.
Power-On-Reset (POR)	The POR can be turned off in standby mode. This monitors V <sub>CC</sub> levels. In the event of unsafe V <sub>CC</sub> drops, this circuit reconfigures the device. When the POR circuitry is turned off, limited power detector circuitry is still active. This option is only recommended for applications in which the power supply rails are reliable.
On-Chip Oscillator	The on-chip oscillator has two power saving features. It may be switched off if it is not needed in your design. It can also be turned off in Standby mode.
PLL	Similar to the on-chip oscillator, the PLL also has two power saving features. It can be statically switched off if it is not needed in a design. It can also be turned off in Standby mode. The PLL will wait until all output clocks from the PLL are driven low before powering off.
I/O Bank Controller	Referenced and differential I/O buffers (used to implement standards such as HSTL, SSTL and LVDS) consume more than ratioed single-ended I/Os such as LVCMOS and LVTTL. The I/O bank controller allows the user to turn these I/Os off dynamically on a per bank selection.
Dynamic Clock Enable for Primary Clock Nets	Each primary clock net can be dynamically disabled to save power.
Power Guard	Power Guard is a feature implemented in input buffers. This feature allows users to switch off the input buffer when it is not needed. This feature can be used in both clock and data paths. Its biggest impact is that in the standby mode it can be used to switch off clock inputs that are distributed using general routing resources.

For more details on the standby mode refer to TN1198, [Power Estimation and Management for MachXO2 Devices](#).

## Power On Reset

MachXO2 devices have power-on reset circuitry to monitor V<sub>CCINT</sub> and V<sub>CCIO</sub> voltage levels during power-up and operation. At power-up, the POR circuitry monitors V<sub>CCINT</sub> and V<sub>CCIO0</sub> (controls configuration) voltage levels. It then triggers download from the on-chip configuration Flash memory after reaching the V<sub>PORUP</sub> level specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. For devices without voltage regulators (ZE and HE devices), V<sub>CCINT</sub> is the same as the V<sub>CC</sub> supply voltage. For devices with voltage regulators (HC devices), V<sub>CCINT</sub> is regulated from the V<sub>CC</sub> supply voltage. From this voltage reference, the time taken for configuration and entry into user mode is specified as Flash Download Time (t<sub>REFRESH</sub>) in the DC and Switching Characteristics section of this data sheet. Before and during configuration, the I/Os are held in tri-state. I/Os are released to user functionality once the device has finished configuration. Note that for HC devices, a separate POR circuit monitors external V<sub>CC</sub> voltage in addition to the POR circuit that monitors the internal post-regulated power supply voltage level.

Once the device enters into user mode, the POR circuitry can optionally continue to monitor V<sub>CCINT</sub> levels. If V<sub>CCINT</sub> drops below V<sub>PORDNBG</sub> level (with the bandgap circuitry switched on) or below V<sub>PORDNSRAM</sub> level (with the bandgap circuitry switched off to conserve power) device functionality cannot be guaranteed. In such a situation the POR issues a reset and begins monitoring the V<sub>CCINT</sub> and V<sub>CCIO</sub> voltage levels. V<sub>PORDNBG</sub> and V<sub>PORDNSRAM</sub> are both specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet.

Note that once a ZE or HE device enters user mode, users can switch off the bandgap to conserve power. When the bandgap circuitry is switched off, the POR circuitry also shuts down. The device is designed such that a minimal, low power POR circuit is still operational (this corresponds to the V<sub>PORDNSRAM</sub> reset point described in the paragraph above). However this circuit is not as accurate as the one that operates when the bandgap is switched on. The low power POR circuit emulates an SRAM cell and is biased to trip before the vast majority of SRAM cells flip. If users are concerned about the V<sub>CC</sub> supply dropping below V<sub>CC</sub> (min) they should not shut down the bandgap or POR circuit.

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## Configuration and Testing

This section describes the configuration and testing features of the MachXO2 family.

### IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO2 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with  $V_{CCIO}$  Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#) and TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#).

### Device Configuration

All MachXO2 devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I<sup>2</sup>C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO2 device:

1. Internal Flash Download
2. JTAG
3. Standard Serial Peripheral Interface (Master SPI mode) – interface to boot PROM memory
4. System microprocessor to drive a serial slave SPI port (SSPI mode)
5. Standard I<sup>2</sup>C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1204, [MachXO2 Programming and Configuration Usage Guide](#) for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO2 devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip Flash memory, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip Flash memory. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) for details.

When implementing background programming of the on-chip Flash, care must be taken for the operation of the PLL. For devices that have two PLLs (XO2-2000U, -4000 and -7000), the system must put the RPLL (Right-side PLL) in reset state during the background Flash programming. More detailed description can be found in TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### **Security and One-Time Programmable Mode (OTP)**

For applications where security is important, the lack of an external bitstream provides a solution that is inherently more secure than SRAM-based FPGAs. This is further enhanced by device locking. MachXO2 devices contain security bits that, when set, prevent the readback of the SRAM configuration and non-volatile Flash memory spaces. The device can be in one of two modes:

1. Unlocked – Readback of the SRAM configuration and non-volatile Flash memory spaces is allowed.
2. Permanently Locked – The device is permanently locked.

Once set, the only way to clear the security bits is to erase the device. To further complement the security of the device, a One Time Programmable (OTP) mode is available. Once the device is set in this mode it is not possible to erase or re-program the Flash and SRAM OTP portions of the device. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### **Dual Boot**

MachXO2 devices can optionally boot from two patterns, a primary bitstream and a golden bitstream. If the primary bitstream is found to be corrupt while being downloaded into the SRAM, the device shall then automatically re-boot from the golden bitstream. Note that the primary bitstream must reside in the on-chip Flash. The golden image MUST reside in an external SPI Flash. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### **Soft Error Detection**

The SED feature is a CRC check of the SRAM cells after the device is configured. This check ensures that the SRAM cells were configured successfully. This feature is enabled by a configuration bit option. The Soft Error Detection can also be initiated in user mode via an input to the fabric. The clock for the Soft Error Detection circuit is generated using a dedicated divider. The undivided clock from the on-chip oscillator is the input to this divider. For low power applications users can switch off the Soft Error Detection circuit. For more details, refer to TN1206, [MachXO2 Soft Error Detection Usage Guide](#).

### **TraceID**

Each MachXO2 device contains a unique (per device), TraceID that can be used for tracking purposes or for IP security applications. The TraceID is 64 bits long. Eight out of 64 bits are user-programmable, the remaining 56 bits are factory-programmed. The TraceID is accessible through the EFB WISHBONE interface and can also be accessed through the SPI, I<sup>2</sup>C, or JTAG interfaces.

### **Density Shifting**

The MachXO2 family has been designed to enable density migration within the same package. Furthermore, the architecture ensures a high success rate when performing design migration from lower density devices to higher density devices. In many cases, it is also possible to shift a lower utilization design targeted for a high-density device to a lower density device. However, the exact details of the final resource utilization will impact the likely success in each case. When migrating from lower to higher density or higher to lower density, ensure to review all the power supplies and NC pins of the chosen devices. For more details refer to the [MachXO2 migration files](#).

Input/Output Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$ Max. (V)	$V_{OH}$ Min. (V)	$I_{OL}$ Max. <sup>4</sup> (mA)	$I_{OH}$ Max. <sup>4</sup> (mA)
	Min. (V) <sup>3</sup>	Max. (V)	Min. (V)	Max. (V)				
LVC MOS10R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	16, 12, 8, 4	NA Open Drain

1. MachXO2 devices allow LVC MOS inputs to be placed in I/O banks where  $V_{CCIO}$  is different from what is specified in the applicable JEDEC specification. This is referred to as a ratioed input buffer. In a majority of cases this operation follows or exceeds the applicable JEDEC specification. The cases where MachXO2 devices do not meet the relevant JEDEC specification are documented in the table below.
2. MachXO2 devices allow for LVC MOS referenced I/Os which follow applicable JEDEC specifications. For more details about mixed mode operation please refer to please refer to TN1202, [MachXO2 sysIO Usage Guide](#).
3. The dual function I<sup>2</sup>C pins SCL and SDA are limited to a  $V_{IL}$  min of -0.25 V or to -0.3 V with a duration of <10 ns.
4. For electromigration, the average DC current sourced or sinked by I/O pads between two consecutive  $V_{CCIO}$  or GND pad connections, or between the last  $V_{CCIO}$  or GND in an I/O bank and the end of an I/O bank, as shown in the Logic Signal Connections table (also shown as I/O grouping) shall not exceed a maximum of  $n * 8$  mA. "n" is the number of I/O pads between the two consecutive bank  $V_{CCIO}$  or GND connections or between the last  $V_{CCIO}$  and GND in a bank and the end of a bank. IO Grouping can be found in the Data Sheet Pin Tables, which can also be generated from the Lattice Diamond software.

Input Standard	$V_{CCIO}$ (V)	$V_{IL}$ Max. (V)
LVC MOS 33	1.5	0.685
LVC MOS 25	1.5	0.687
LVC MOS 18	1.5	0.655

## sysIO Differential Electrical Characteristics

The LVDS differential output buffers are available on the top side of MachXO2-640U, MachXO2-1200/U and higher density devices in the MachXO2 PLD family.

## LVDS

### Over Recommended Operating Conditions

Parameter Symbol	Parameter Description	Test Conditions	Min.	Typ.	Max.	Units
$V_{INP}$ $V_{INM}$	Input Voltage	$V_{CCIO} = 3.3$ V	0	—	2.605	V
		$V_{CCIO} = 2.5$ V	0	—	2.05	V
$V_{THD}$	Differential Input Threshold		±100	—		mV
$V_{CM}$	Input Common Mode Voltage	$V_{CCIO} = 3.3$ V	0.05	—	2.6	V
		$V_{CCIO} = 2.5$ V	0.05	—	2.0	V
$I_{IN}$	Input current	Power on	—	—	±10	μA
$V_{OH}$	Output high voltage for $V_{OP}$ or $V_{OM}$	$R_T = 100$ Ohm	—	1.375	—	V
$V_{OL}$	Output low voltage for $V_{OP}$ or $V_{OM}$	$R_T = 100$ Ohm	0.90	1.025	—	V
$V_{OD}$	Output voltage differential	$(V_{OP} - V_{OM})$ , $R_T = 100$ Ohm	250	350	450	mV
$\Delta V_{OD}$	Change in $V_{OD}$ between high and low		—	—	50	mV
$V_{OS}$	Output voltage offset	$(V_{OP} + V_{OM})/2$ , $R_T = 100$ Ohm	1.125	1.20	1.395	V
$\Delta V_{OS}$	Change in $V_{OS}$ between H and L		—	—	50	mV
$I_{OSD}$	Output short circuit current	$V_{OD} = 0$ V driver outputs shorted	—	—	24	mA

Parameter	Description	Device	-6		-5		-4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>HPLL</sub>	Clock to Data Hold – PIO Input Register	MachXO2-1200HC-HE	0.41	—	0.48	—	0.55	—	ns
		MachXO2-2000HC-HE	0.42	—	0.49	—	0.56	—	ns
		MachXO2-4000HC-HE	0.43	—	0.50	—	0.58	—	ns
		MachXO2-7000HC-HE	0.46	—	0.54	—	0.62	—	ns
t <sub>SU_DELPLL</sub>	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-1200HC-HE	2.88	—	3.19	—	3.72	—	ns
		MachXO2-2000HC-HE	2.87	—	3.18	—	3.70	—	ns
		MachXO2-4000HC-HE	2.96	—	3.28	—	3.81	—	ns
		MachXO2-7000HC-HE	3.05	—	3.35	—	3.87	—	ns
t <sub>H_DELPLL</sub>	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-1200HC-HE	–0.83	—	–0.83	—	–0.83	—	ns
		MachXO2-2000HC-HE	–0.83	—	–0.83	—	–0.83	—	ns
		MachXO2-4000HC-HE	–0.87	—	–0.87	—	–0.87	—	ns
		MachXO2-7000HC-HE	–0.91	—	–0.91	—	–0.91	—	ns
Generic DDRX1 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR1_RX.SCLK.Aligned <sup>9, 12</sup>									
t <sub>DVA</sub>	Input Data Valid After CLK	All MachXO2 devices, all sides	—	0.317	—	0.344	—	0.368	UI
t <sub>DVE</sub>	Input Data Hold After CLK		0.742	—	0.702	—	0.668	—	UI
f <sub>DATA</sub>	DDRX1 Input Data Speed		—	300	—	250	—	208	Mbps
f <sub>DDRX1</sub>	DDRX1 SCLK Frequency		—	150	—	125	—	104	MHz
Generic DDRX1 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR1_RX.SCLK.Centered <sup>9, 12</sup>									
t <sub>SU</sub>	Input Data Setup Before CLK	All MachXO2 devices, all sides	0.566	—	0.560	—	0.538	—	ns
t <sub>HO</sub>	Input Data Hold After CLK		0.778	—	0.879	—	1.090	—	ns
f <sub>DATA</sub>	DDRX1 Input Data Speed		—	300	—	250	—	208	Mbps
f <sub>DDRX1</sub>	DDRX1 SCLK Frequency		—	150	—	125	—	104	MHz
Generic DDRX2 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR2_RX.ECLK.Aligned <sup>9, 12</sup>									
t <sub>DVA</sub>	Input Data Valid After CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only <sup>11</sup>	—	0.316	—	0.342	—	0.364	UI
t <sub>DVE</sub>	Input Data Hold After CLK		0.710	—	0.675	—	0.679	—	UI
f <sub>DATA</sub>	DDRX2 Serial Input Data Speed		—	664	—	554	—	462	Mbps
f <sub>DDRX2</sub>	DDRX2 ECLK Frequency		—	332	—	277	—	231	MHz
f <sub>SCLK</sub>	SCLK Frequency		—	166	—	139	—	116	MHz
Generic DDRX2 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR2_RX.ECLK.Centered <sup>9, 12</sup>									
t <sub>SU</sub>	Input Data Setup Before CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only <sup>11</sup>	0.233	—	0.219	—	0.198	—	ns
t <sub>HO</sub>	Input Data Hold After CLK		0.287	—	0.287	—	0.344	—	ns
f <sub>DATA</sub>	DDRX2 Serial Input Data Speed		—	664	—	554	—	462	Mbps
f <sub>DDRX2</sub>	DDRX2 ECLK Frequency		—	332	—	277	—	231	MHz
f <sub>SCLK</sub>	SCLK Frequency		—	166	—	139	—	116	MHz

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
LPDDR <sup>9, 12</sup>									
t <sub>DVADQ</sub>	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. <sup>13</sup>	—	0.349	—	0.381	—	0.396	UI
t <sub>DVEDQ</sub>	Input Data Hold After DQS Input		0.665	—	0.630	—	0.613	—	UI
t <sub>DQVBS</sub>	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t <sub>DQVAS</sub>	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f <sub>DATA</sub>	MEM LPDDR Serial Data Speed		—	120	—	110	—	96	Mbps
f <sub>SCLK</sub>	SCLK Frequency		—	60	—	55	—	48	MHz
f <sub>LPDDR</sub>	LPDDR Data Transfer Rate		0	120	0	110	0	96	Mbps
DDR <sup>9, 12</sup>									
t <sub>DVADQ</sub>	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. <sup>13</sup>	—	0.347	—	0.374	—	0.393	UI
t <sub>DVEDQ</sub>	Input Data Hold After DQS Input		0.665	—	0.637	—	0.616	—	UI
t <sub>DQVBS</sub>	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t <sub>DQVAS</sub>	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f <sub>DATA</sub>	MEM DDR Serial Data Speed		—	140	—	116	—	98	Mbps
f <sub>SCLK</sub>	SCLK Frequency		—	70	—	58	—	49	MHz
f <sub>MEM_DDR</sub>	MEM DDR Data Transfer Rate		N/A	140	N/A	116	N/A	98	Mbps
DDR2 <sup>9, 12</sup>									
t <sub>DVADQ</sub>	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. <sup>13</sup>	—	0.372	—	0.394	—	0.410	UI
t <sub>DVEDQ</sub>	Input Data Hold After DQS Input		0.690	—	0.658	—	0.618	—	UI
t <sub>DQVBS</sub>	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t <sub>DQVAS</sub>	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f <sub>DATA</sub>	MEM DDR Serial Data Speed		—	140	—	116	—	98	Mbps
f <sub>SCLK</sub>	SCLK Frequency		—	70	—	58	—	49	MHz
f <sub>MEM_DDR2</sub>	MEM DDR2 Data Transfer Rate		N/A	140	N/A	116	N/A	98	Mbps

- Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.
- General I/O timing numbers based on LVCMOS 2.5, 8 mA, 0 pF load, fast slew rate.
- Generic DDR timing numbers based on LVDS I/O (for input, output, and clock ports).
- DDR timing numbers based on SSTL25. DDR2 timing numbers based on SSTL18. LPDDR timing numbers based in LVCMOS18.
- 7:1 LVDS (GDDR71) uses the LVDS I/O standard (for input, output, and clock ports).
- For Generic DDRX1 mode  $t_{SU} = t_{HO} = (t_{DVE} - t_{DVA} - 0.03 \text{ ns})/2$ .
- The  $t_{SU\_DEL}$  and  $t_{H\_DEL}$  values use the SCLK\_ZERHOLD default step size. Each step is 167 ps (-3), 182 ps (-2), 195 ps (-1).
- This number for general purpose usage. Duty cycle tolerance is +/-10%.
- Duty cycle is +/- 5% for system usage.
- The above timing numbers are generated using the Diamond design tool. Exact performance may vary with the device selected.
- High-speed DDR and LVDS not supported in SG32 (32-Pin QFN) packages.
- Advance information for MachXO2 devices in 48 QFN packages.
- DDR memory interface not supported in QN84 (84 QFN) and SG32 (32 QFN) packages.

## Flash Download Time<sup>1, 2</sup>

Symbol	Parameter	Device	Typ.	Units
$t_{\text{REFRESH}}$	POR to Device I/O Active	LCMXO2-256	0.6	ms
		LCMXO2-640	1.0	ms
		LCMXO2-640U	1.9	ms
		LCMXO2-1200	1.9	ms
		LCMXO2-1200U	1.4	ms
		LCMXO2-2000	1.4	ms
		LCMXO2-2000U	2.4	ms
		LCMXO2-4000	2.4	ms
		LCMXO2-7000	3.8	ms

1. Assumes sysMEM EBR initialized to an all zero pattern if they are used.
2. The Flash download time is measured starting from the maximum voltage of POR trip point.

## JTAG Port Timing Specifications

Symbol	Parameter	Min.	Max.	Units
$f_{\text{MAX}}$	TCK clock frequency	—	25	MHz
$t_{\text{BTCPH}}$	TCK [BSCAN] clock pulse width high	20	—	ns
$t_{\text{BTCPL}}$	TCK [BSCAN] clock pulse width low	20	—	ns
$t_{\text{BTS}}$	TCK [BSCAN] setup time	10	—	ns
$t_{\text{BTH}}$	TCK [BSCAN] hold time	8	—	ns
$t_{\text{BTCO}}$	TAP controller falling edge of clock to valid output	—	10	ns
$t_{\text{BTCODIS}}$	TAP controller falling edge of clock to valid disable	—	10	ns
$t_{\text{BTCOEN}}$	TAP controller falling edge of clock to valid enable	—	10	ns
$t_{\text{BTCRS}}$	BSCAN test capture register setup time	8	—	ns
$t_{\text{BTCRH}}$	BSCAN test capture register hold time	20	—	ns
$t_{\text{BUTCO}}$	BSCAN test update register, falling edge of clock to valid output	—	25	ns
$t_{\text{BTUODIS}}$	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
$t_{\text{BTUPOEN}}$	BSCAN test update register, falling edge of clock to valid enable	—	25	ns

## sysCONFIG Port Timing Specifications

Symbol	Parameter		Min.	Max.	Units
All Configuration Modes					
t <sub>PRGM</sub>	PROGRAMN low pulse accept		55	—	ns
t <sub>PRGMJ</sub>	PROGRAMN low pulse rejection		—	25	ns
t <sub>INITL</sub>	INITN low time	LCMXO2-256	—	30	μs
		LCMXO2-640	—	35	μs
		LCMXO2-640U/ LCMXO2-1200	—	55	μs
		LCMXO2-1200U/ LCMXO2-2000	—	70	μs
		LCMXO2-2000U/ LCMXO2-4000	—	105	μs
		LCMXO2-7000	—	130	μs
t <sub>DPPINIT</sub>	PROGRAMN low to INITN low		—	150	ns
t <sub>DPPDONE</sub>	PROGRAMN low to DONE low		—	150	ns
t <sub>IODISS</sub>	PROGRAMN low to I/O disable		—	120	ns
Slave SPI					
f <sub>MAX</sub>	CCLK clock frequency		—	66	MHz
t <sub>CCLKH</sub>	CCLK clock pulse width high		7.5	—	ns
t <sub>CCLKL</sub>	CCLK clock pulse width low		7.5	—	ns
t <sub>STSU</sub>	CCLK setup time		2	—	ns
t <sub>STH</sub>	CCLK hold time		0	—	ns
t <sub>STCO</sub>	CCLK falling edge to valid output		—	10	ns
t <sub>STOZ</sub>	CCLK falling edge to valid disable		—	10	ns
t <sub>STOV</sub>	CCLK falling edge to valid enable		—	10	ns
t <sub>SCS</sub>	Chip select high time		25	—	ns
t <sub>SCSS</sub>	Chip select setup time		3	—	ns
t <sub>SCSH</sub>	Chip select hold time		3	—	ns
Master SPI					
f <sub>MAX</sub>	MCLK clock frequency		—	133	MHz
t <sub>MCLKH</sub>	MCLK clock pulse width high		3.75	—	ns
t <sub>MCLKL</sub>	MCLK clock pulse width low		3.75	—	ns
t <sub>STSU</sub>	MCLK setup time		5	—	ns
t <sub>STH</sub>	MCLK hold time		1	—	ns
t <sub>CSSPI</sub>	INITN high to chip select low		100	200	ns
t <sub>MCLK</sub>	INITN high to first MCLK edge		0.75	1	μs

### I<sup>2</sup>C Port Timing Specifications<sup>1, 2</sup>

Symbol	Parameter	Min.	Max.	Units
f <sub>MAX</sub>	Maximum SCL clock frequency	—	400	kHz

- MachXO2 supports the following modes:
  - Standard-mode (Sm), with a bit rate up to 100 kbit/s (user and configuration mode)
  - Fast-mode (Fm), with a bit rate up to 400 kbit/s (user and configuration mode)
- Refer to the I<sup>2</sup>C specification for timing requirements.

### SPI Port Timing Specifications<sup>1</sup>

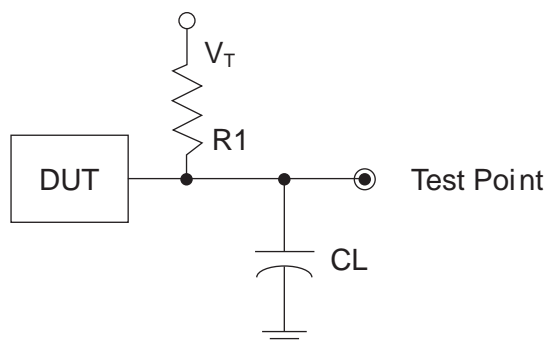
Symbol	Parameter	Min.	Max.	Units
f <sub>MAX</sub>	Maximum SCK clock frequency	—	45	MHz

- Applies to user mode only. For configuration mode timing specifications, refer to sysCONFIG Port Timing Specifications table in this data sheet.

### Switching Test Conditions

Figure 3-13 shows the output test load used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are shown in Table 3-5.

**Figure 3-13. Output Test Load, LVTTTL and LVCMOS Standards**



**Table 3-5. Test Fixture Required Components, Non-Terminated Interfaces**

Test Condition	R1	CL	Timing Ref.	VT
LVTTTL and LVCMOS settings (L -> H, H -> L)	$\infty$	0pF	LVTTTL, LVCMOS 3.3 = 1.5 V	—
			LVCMOS 2.5 = V <sub>CCIO</sub> /2	—
			LVCMOS 1.8 = V <sub>CCIO</sub> /2	—
			LVCMOS 1.5 = V <sub>CCIO</sub> /2	—
			LVCMOS 1.2 = V <sub>CCIO</sub> /2	—
LVTTTL and LVCMOS 3.3 (Z -> H)	188	0pF	1.5 V	V <sub>OL</sub>
LVTTTL and LVCMOS 3.3 (Z -> L)			1.5 V	V <sub>OH</sub>
Other LVCMOS (Z -> H)			V <sub>CCIO</sub> /2	V <sub>OL</sub>
Other LVCMOS (Z -> L)			V <sub>CCIO</sub> /2	V <sub>OH</sub>
LVTTTL + LVCMOS (H -> Z)			V <sub>OH</sub> - 0.15 V	V <sub>OL</sub>
LVTTTL + LVCMOS (L -> Z)			V <sub>OL</sub> - 0.15 V	V <sub>OH</sub>

Note: Output test conditions for all other interfaces are determined by the respective standards.

	MachXO2-4000							
	84 QFN	132 csBGA	144 TQFP	184 csBGA	256 caBGA	256 ftBGA	332 caBGA	484 fpBGA
<b>General Purpose I/O per Bank</b>								
Bank 0	27	25	27	37	50	50	68	70
Bank 1	10	26	29	37	52	52	68	68
Bank 2	22	28	29	39	52	52	70	72
Bank 3	0	7	9	10	16	16	24	24
Bank 4	9	8	10	12	16	16	16	16
Bank 5	0	10	10	15	20	20	28	28
Total General Purpose Single Ended I/O	68	104	114	150	206	206	274	278
<b>Differential I/O per Bank</b>								
Bank 0	13	13	14	18	25	25	34	35
Bank 1	4	13	14	18	26	26	34	34
Bank 2	11	14	14	19	26	26	35	36
Bank 3	0	3	4	4	8	8	12	12
Bank 4	4	4	5	6	8	8	8	8
Bank 5	0	5	5	7	10	10	14	14
Total General Purpose Differential I/O	32	52	56	72	103	103	137	139
<b>Dual Function I/O</b>								
	28	37	37	37	37	37	37	37
<b>High-speed Differential I/O</b>								
Bank 0	8	8	9	8	18	18	18	18
<b>Gearboxes</b>								
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	8	8	9	9	18	18	18	18
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	11	14	14	12	18	18	18	18
<b>DQS Groups</b>								
Bank 1	1	2	2	2	2	2	2	2
<b>VCCIO Pins</b>								
Bank 0	3	3	3	3	4	4	4	10
Bank 1	1	3	3	3	4	4	4	10
Bank 2	2	3	3	3	4	4	4	10
Bank 3	1	1	1	1	1	1	2	3
Bank 4	1	1	1	1	2	2	1	4
Bank 5	1	1	1	1	1	1	2	3
<b>VCC</b>								
	4	4	4	4	8	8	8	12
<b>GND</b>								
	4	10	12	16	24	24	27	48
<b>NC</b>								
	1	1	1	1	1	1	5	105
<b>Reserved for configuration</b>								
	1	1	1	1	1	1	1	1
Total Count of Bonded Pins	84	132	144	184	256	256	332	484

	MachXO2-7000					
	144 TQFP	256 caBGA	256 ftBGA	332 caBGA	400 caBGA	484 fpBGA
<b>General Purpose I/O per Bank</b>						
Bank 0	27	50	50	68	83	82
Bank 1	29	52	52	70	84	84
Bank 2	29	52	52	70	84	84
Bank 3	9	16	16	24	28	28
Bank 4	10	16	16	16	24	24
Bank 5	10	20	20	30	32	32
Total General Purpose Single Ended I/O	114	206	206	278	335	334
<b>Differential I/O per Bank</b>						
Bank 0	14	25	25	34	42	41
Bank 1	14	26	26	35	42	42
Bank 2	14	26	26	35	42	42
Bank 3	4	8	8	12	14	14
Bank 4	5	8	8	8	12	12
Bank 5	5	10	10	15	16	16
Total General Purpose Differential I/O	56	103	103	139	168	167
<b>Dual Function I/O</b>						
	37	37	37	37	37	37
<b>High-speed Differential I/O</b>						
Bank 0	9	20	20	21	21	21
<b>Gearboxes</b>						
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	9	20	20	21	21	21
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	14	20	20	21	21	21
<b>DQS Groups</b>						
Bank 1	2	2	2	2	2	2
<b>VCCIO Pins</b>						
Bank 0	3	4	4	4	5	10
Bank 1	3	4	4	4	5	10
Bank 2	3	4	4	4	5	10
Bank 3	1	1	1	2	2	3
Bank 4	1	2	2	1	2	4
Bank 5	1	1	1	2	2	3
VCC	4	8	8	8	10	12
GND	12	24	24	27	33	48
NC	1	1	1	1	0	49
Reserved for Configuration	1	1	1	1	1	1
Total Count of Bonded Pins	144	256	256	332	400	484

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000HC-4TG144C	6864	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	COM
LCMXO2-7000HC-5TG144C	6864	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	COM
LCMXO2-7000HC-6TG144C	6864	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	COM
LCMXO2-7000HC-4BG256C	6864	2.5 V / 3.3 V	–4	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-5BG256C	6864	2.5 V / 3.3 V	–5	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-6BG256C	6864	2.5 V / 3.3 V	–6	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-4FTG256C	6864	2.5 V / 3.3 V	–4	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-5FTG256C	6864	2.5 V / 3.3 V	–5	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-6FTG256C	6864	2.5 V / 3.3 V	–6	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-4BG332C	6864	2.5 V / 3.3 V	–4	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-5BG332C	6864	2.5 V / 3.3 V	–5	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-6BG332C	6864	2.5 V / 3.3 V	–6	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-4FG400C	6864	2.5 V / 3.3 V	–4	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-5FG400C	6864	2.5 V / 3.3 V	–5	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-6FG400C	6864	2.5 V / 3.3 V	–6	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-4FG484C	6864	2.5 V / 3.3 V	–4	Halogen-Free fpBGA	484	COM
LCMXO2-7000HC-5FG484C	6864	2.5 V / 3.3 V	–5	Halogen-Free fpBGA	484	COM
LCMXO2-7000HC-6FG484C	6864	2.5 V / 3.3 V	–6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4TG100CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-5TG100CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-6TG100CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-4MG132CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-5MG132CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-6MG132CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-4TG144CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	COM
LCMXO2-1200HC-5TG144CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	COM
LCMXO2-1200HC-6TG144CR1 <sup>1</sup>	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	COM

1. Specifications for the “LCMXO2-1200HC-speed package CR1” are the same as the “LCMXO2-1200HC-speed package C” devices respectively, except as specified in the [R1 Device Specifications](#) section of this data sheet.

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000HE-6BG332C	4320	1.2 V	–6	Halogen-Free caBGA	332	COM
LCMXO2-4000HE-4FG484C	4320	1.2 V	–4	Halogen-Free fpBGA	484	COM
LCMXO2-4000HE-5FG484C	4320	1.2 V	–5	Halogen-Free fpBGA	484	COM
LCMXO2-4000HE-6FG484C	4320	1.2 V	–6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000HE-4TG144C	6864	1.2 V	–4	Halogen-Free TQFP	144	COM
LCMXO2-7000HE-5TG144C	6864	1.2 V	–5	Halogen-Free TQFP	144	COM
LCMXO2-7000HE-6TG144C	6864	1.2 V	–6	Halogen-Free TQFP	144	COM
LCMXO2-7000HE-4BG256C	6864	1.2 V	–4	Halogen-Free caBGA	256	COM
LCMXO2-7000HE-5BG256C	6864	1.2 V	–5	Halogen-Free caBGA	256	COM
LCMXO2-7000HE-6BG256C	6864	1.2 V	–6	Halogen-Free caBGA	256	COM
LCMXO2-7000HE-4FTG256C	6864	1.2 V	–4	Halogen-Free ftBGA	256	COM
LCMXO2-7000HE-5FTG256C	6864	1.2 V	–5	Halogen-Free ftBGA	256	COM
LCMXO2-7000HE-6FTG256C	6864	1.2 V	–6	Halogen-Free ftBGA	256	COM
LCMXO2-7000HE-4BG332C	6864	1.2 V	–4	Halogen-Free caBGA	332	COM
LCMXO2-7000HE-5BG332C	6864	1.2 V	–5	Halogen-Free caBGA	332	COM
LCMXO2-7000HE-6BG332C	6864	1.2 V	–6	Halogen-Free caBGA	332	COM
LCMXO2-7000HE-4FG484C	6864	1.2 V	–4	Halogen-Free fpBGA	484	COM
LCMXO2-7000HE-5FG484C	6864	1.2 V	–5	Halogen-Free fpBGA	484	COM
LCMXO2-7000HE-6FG484C	6864	1.2 V	–6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4SG32I	1280	2.5 V / 3.3 V	–4	Halogen-Free QFN	32	IND
LCMXO2-1200HC-5SG32I	1280	2.5 V / 3.3 V	–5	Halogen-Free QFN	32	IND
LCMXO2-1200HC-6SG32I	1280	2.5 V / 3.3 V	–6	Halogen-Free QFN	32	IND
LCMXO2-1200HC-4TG100I	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-5TG100I	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-6TG100I	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-4MG132I	1280	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-5MG132I	1280	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-6MG132I	1280	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-4TG144I	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-5TG144I	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-6TG144I	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200UHC-4FTG256I	1280	2.5 V / 3.3 V	–4	Halogen-Free ftBGA	256	IND
LCMXO2-1200UHC-5FTG256I	1280	2.5 V / 3.3 V	–5	Halogen-Free ftBGA	256	IND
LCMXO2-1200UHC-6FTG256I	1280	2.5 V / 3.3 V	–6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HC-4TG100I	2112	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-5TG100I	2112	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-6TG100I	2112	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-4MG132I	2112	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-5MG132I	2112	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-6MG132I	2112	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-4TG144I	2112	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-5TG144I	2112	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-6TG144I	2112	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-4BG256I	2112	2.5 V / 3.3 V	–4	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-5BG256I	2112	2.5 V / 3.3 V	–5	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-6BG256I	2112	2.5 V / 3.3 V	–6	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-4FTG256I	2112	2.5 V / 3.3 V	–4	Halogen-Free ftBGA	256	IND
LCMXO2-2000HC-5FTG256I	2112	2.5 V / 3.3 V	–5	Halogen-Free ftBGA	256	IND
LCMXO2-2000HC-6FTG256I	2112	2.5 V / 3.3 V	–6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHC-4FG484I	2112	2.5 V / 3.3 V	–4	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHC-5FG484I	2112	2.5 V / 3.3 V	–5	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHC-6FG484I	2112	2.5 V / 3.3 V	–6	Halogen-Free fpBGA	484	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000HE-4MG132I	4320	1.2 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-4000HE-5MG132I	4320	1.2 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-4000HE-6MG132I	4320	1.2 V	–6	Halogen-Free csBGA	132	IND
LCMXO2-4000HE-4TG144I	4320	1.2 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-4000HE-5TG144I	4320	1.2 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-4000HE-6TG144I	4320	1.2 V	–6	Halogen-Free TQFP	144	IND
LCMXO2-4000HE-4MG184I	4320	1.2 V	–4	Halogen-Free csBGA	184	IND
LCMXO2-4000HE-5MG184I	4320	1.2 V	–5	Halogen-Free csBGA	184	IND
LCMXO2-4000HE-6MG184I	4320	1.2 V	–6	Halogen-Free csBGA	184	IND
LCMXO2-4000HE-4BG256I	4320	1.2 V	–4	Halogen-Free caBGA	256	IND
LCMXO2-4000HE-5BG256I	4320	1.2 V	–5	Halogen-Free caBGA	256	IND
LCMXO2-4000HE-6BG256I	4320	1.2 V	–6	Halogen-Free caBGA	256	IND
LCMXO2-4000HE-4FTG256I	4320	1.2 V	–4	Halogen-Free ftBGA	256	IND
LCMXO2-4000HE-5FTG256I	4320	1.2 V	–5	Halogen-Free ftBGA	256	IND
LCMXO2-4000HE-6FTG256I	4320	1.2 V	–6	Halogen-Free ftBGA	256	IND
LCMXO2-4000HE-4BG332I	4320	1.2 V	–4	Halogen-Free caBGA	332	IND
LCMXO2-4000HE-5BG332I	4320	1.2 V	–5	Halogen-Free caBGA	332	IND
LCMXO2-4000HE-6BG332I	4320	1.2 V	–6	Halogen-Free caBGA	332	IND
LCMXO2-4000HE-4FG484I	4320	1.2 V	–4	Halogen-Free fpBGA	484	IND
LCMXO2-4000HE-5FG484I	4320	1.2 V	–5	Halogen-Free fpBGA	484	IND
LCMXO2-4000HE-6FG484I	4320	1.2 V	–6	Halogen-Free fpBGA	484	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000HE-4TG144I	6864	1.2 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-7000HE-5TG144I	6864	1.2 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-7000HE-6TG144I	6864	1.2 V	–6	Halogen-Free TQFP	144	IND
LCMXO2-7000HE-4BG256I	6864	1.2 V	–4	Halogen-Free caBGA	256	IND
LCMXO2-7000HE-5BG256I	6864	1.2 V	–5	Halogen-Free caBGA	256	IND
LCMXO2-7000HE-6BG256I	6864	1.2 V	–6	Halogen-Free caBGA	256	IND
LCMXO2-7000HE-4FTG256I	6864	1.2 V	–4	Halogen-Free ftBGA	256	IND
LCMXO2-7000HE-5FTG256I	6864	1.2 V	–5	Halogen-Free ftBGA	256	IND
LCMXO2-7000HE-6FTG256I	6864	1.2 V	–6	Halogen-Free ftBGA	256	IND
LCMXO2-7000HE-4BG332I	6864	1.2 V	–4	Halogen-Free caBGA	332	IND
LCMXO2-7000HE-5BG332I	6864	1.2 V	–5	Halogen-Free caBGA	332	IND
LCMXO2-7000HE-6BG332I	6864	1.2 V	–6	Halogen-Free caBGA	332	IND
LCMXO2-7000HE-4FG484I	6864	1.2 V	–4	Halogen-Free fpBGA	484	IND
LCMXO2-7000HE-5FG484I	6864	1.2 V	–5	Halogen-Free fpBGA	484	IND
LCMXO2-7000HE-6FG484I	6864	1.2 V	–6	Halogen-Free fpBGA	484	IND

## R1 Device Specifications

The LCMXO2-1200ZE/HC “R1” devices have the same specifications as their Standard (non-R1) counterparts except as listed below. For more details on the R1 to Standard migration refer to AN8086, [Designing for Migration from MachXO2-1200-R1 to Standard Non-R1\) Devices](#).

- The User Flash Memory (UFM) cannot be programmed through the internal WISHBONE interface. It can still be programmed through the JTAG/SPI/I<sup>2</sup>C ports.
- The on-chip differential input termination resistor value is higher than intended. It is approximately 200Ω as opposed to the intended 100Ω. It is recommended to use external termination resistors for differential inputs. The on-chip termination resistors can be disabled through Lattice design software.
- Soft Error Detection logic may not produce the correct result when it is run for the first time after configuration. To use this feature, discard the result from the first operation. Subsequent operations will produce the correct result.
- Under certain conditions, I<sub>IH</sub> exceeds data sheet specifications. The following table provides more details:

Condition	Clamp	Pad Rising I <sub>IH</sub> Max.	Pad Falling I <sub>IH</sub> Min.	Steady State Pad High I <sub>IH</sub>	Steady State Pad Low I <sub>IL</sub>
VPAD > VCCIO	OFF	1 mA	–1 mA	1 mA	10 μA
VPAD = VCCIO	ON	10 μA	–10 μA	10 μA	10 μA
VPAD = VCCIO	OFF	1 mA	–1 mA	1 mA	10 μA
VPAD < VCCIO	OFF	10 μA	–10 μA	10 μA	10 μA

- The user SPI interface does not operate correctly in some situations. During master read access and slave write access, the last byte received does not generate the RRDY interrupt.
- In GDDR2, GDDR4 and GDDR71 modes, ECLKSYNC may have a glitch in the output under certain conditions, leading to possible loss of synchronization.
- When using the hard I<sup>2</sup>C IP core, the I<sup>2</sup>C status registers I2C\_1\_SR and I2C\_2\_SR may not update correctly.
- PLL Lock signal will glitch high when coming out of standby. This glitch lasts for about 10 μsec before returning low.
- Dual boot only available on HC devices, requires tying VCC and VCCIO2 to the same 3.3 V or 2.5 V supply.

### For Further Information

A variety of technical notes for the MachXO2 family are available on the Lattice web site.

- TN1198, [Power Estimation and Management for MachXO2 Devices](#)
- TN1199, [MachXO2 sysCLOCK PLL Design and Usage Guide](#)
- TN1201, [Memory Usage Guide for MachXO2 Devices](#)
- TN1202, [MachXO2 sysIO Usage Guide](#)
- TN1203, [Implementing High-Speed Interfaces with MachXO2 Devices](#)
- TN1204, [MachXO2 Programming and Configuration Usage Guide](#)
- TN1205, [Using User Flash Memory and Hardened Control Functions in MachXO2 Devices](#)
- TN1206, [MachXO2 SRAM CRC Error Detection Usage Guide](#)
- TN1207, [Using TraceID in MachXO2 Devices](#)
- TN1074, [PCB Layout Recommendations for BGA Packages](#)
- TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#)
- AN8086, [Designing for Migration from MachXO2-1200-R1 to Standard \(non-R1\) Devices](#)
- AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#)
- [MachXO2 Device Pinout Files](#)
- [Thermal Management](#) document
- [Lattice design tools](#)

For further information on interface standards, refer to the following web sites:

- JEDEC Standards (LVTTTL, LVCMOS, LVDS, DDR, DDR2, LPDDR): [www.jedec.org](http://www.jedec.org)
- PCI: [www.pcisig.com](http://www.pcisig.com)